

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. MICRON.111C1	APPLICATION NO. Unknown	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)				APPLICANT Raina, et al.		
				FILING DATE Herewith	GROUP 2879	

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
S.R.	1	4,084,986	04/18/78	Aoki, et al.	148	1.5	4/19/76
S.R.	2	4,940,916	07-1990	Borel, et al.	313	306	11/3/88
S.R.	3	5,585,301	12-1996	Lee, et al.	313	306	7/14/95
S.R.	4	5,714,415	02/03/98	Oguro	438	486	1/29/96
S.R.	5	5,789,851	08-1998	Turlot, et al.	313	309	12/15/95
S.R.	6	5,866,930	02-1999	Salda, et al.	257	316	8/26/96
S.R.	7	5,902,650	05-1999	Feng, et al.	427	578	7/11/95
S.R.	8	6,015,323	01/18/00	Moradi, et al.	445	24	1/3/97
S.R.	9	6,019,657	02-2000	Chakvorty, et al.	445	24	10/29/98
S.R.	10	6,064,149	05/16/00	Raina	313	497	2/23/98
S.R.	11	6,181,308	01/30/01	Cathey, et al.	345	75.2	8/21/96
S.R.	12	6,190,929	02-2001	Wang, et al.	438	20	7/23/99
S.R.	13	6,211,608	04-2001	Raina, et al.	313	309	6/11/98

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
S.R.	14	JP 04168763 A	06-1992	Japan	H01L	27/04	

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
S.R.	15	Young-Chang Joo, et al. 1996. Electromigration in single-crystal aluminum lines pre-damaged by nanoindentation, <i>Materials Research Society Symp. Proc.</i> , 428:225-230.
S.R.	16	Atsushi Masuda, et al. 15 May 1997. Nitrogen-doping effects on electrical, optical, and structural properties in hydrogenated amorphous silicon. <i>American Institute of Physics. J. Appl. Phys.</i> , 81(10):6729-6737.
S.R.	17	C-K. Hu, et al. 1993. Electromigration damage in fine Al alloy lines due to interfacial diffusion. <i>Materials Research Society Symp. Proc.</i> , 309:111-120.

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EXAMINER	Sikha Roy	DATE CONSIDERED	6/9/04
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			